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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.6GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-CLGA, FCCLGA
Supplier Device Package	360-FCCLGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc7448vs1600lc

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Features

— Four vector units and 32-entry vector register file (VRs)

- Vector permute unit (VPU)
- − Vector integer unit 1 (VIU1) handles short-latency AltiVecTM integer instructions, such as vector add instructions (for example, vaddsbs, vaddsbs, and vaddsws).
- Vector integer unit 2 (VIU2) handles longer-latency AltiVec integer instructions, such as vector multiply add instructions (for example, vmhaddshs, vmhraddshs, and vmladduhm).
- Vector floating-point unit (VFPU)
- Three-stage load/store unit (LSU)
 - Supports integer, floating-point, and vector instruction load/store traffic
 - Four-entry vector touch queue (VTQ) supports all four architected AltiVec data stream operations
 - Three-cycle GPR and AltiVec load latency (byte, half word, word, vector) with one-cycle throughput
 - Four-cycle FPR load latency (single, double) with one-cycle throughput
 - No additional delay for misaligned access within double-word boundary
 - A dedicated adder calculates effective addresses (EAs).
 - Supports store gathering
 - Performs alignment, normalization, and precision conversion for floating-point data
 - Executes cache control and TLB instructions
 - Performs alignment, zero padding, and sign extension for integer data
 - Supports hits under misses (multiple outstanding misses)
 - Supports both big- and little-endian modes, including misaligned little-endian accesses
- Three issue queues, FIQ, VIQ, and GIQ, can accept as many as one, two, and three instructions, respectively, in a cycle. Instruction dispatch requires the following:
 - Instructions can only be dispatched from the three lowest IQ entries—IQ0, IQ1, and IQ2.
 - A maximum of three instructions can be dispatched to the issue queues per clock cycle.
 - Space must be available in the CQ for an instruction to dispatch (this includes instructions that are assigned a space in the CQ but not in an issue queue).
- Rename buffers
 - 16 GPR rename buffers
 - 16 FPR rename buffers
 - 16 VR rename buffers
- Dispatch unit
 - Decode/dispatch stage fully decodes each instruction
- Completion unit
 - Retires an instruction from the 16-entry completion queue (CQ) when all instructions ahead of it have been completed, the instruction has finished executing, and no exceptions are pending
 - Guarantees sequential programming model (precise exception model)



Features

- Efficient data flow
 - Although the VR/LSU interface is 128 bits, the L1/L2 bus interface allows up to 256 bits.
 - The L1 data cache is fully pipelined to provide 128 bits/cycle to or from the VRs.
 - The L2 cache is fully pipelined to provide 32 bytes per clock every other cycle to the L1 caches.
 - As many as 16 out-of-order transactions can be present on the MPX bus.
 - Store merging for multiple store misses to the same line. Only coherency action taken (address-only) for store misses merged to all 32 bytes of a cache block (no data tenure needed).
 - Three-entry finished store queue and five-entry completed store queue between the LSU and the L1 data cache
 - Separate additional queues for efficient buffering of outbound data (such as castouts and write-through stores) from the L1 data cache and L2 cache
- Multiprocessing support features include the following:
 - Hardware-enforced, MESI cache coherency protocols for data cache
 - Load/store with reservation instruction pair for atomic memory references, semaphores, and other multiprocessor operations
- Power and thermal management
 - Dynamic frequency switching (DFS) feature allows processor core frequency to be halved or quartered through software to reduce power consumption.
 - The following three power-saving modes are available to the system:
 - Nap—Instruction fetching is halted. Only the clocks for the time base, decrementer, and JTAG logic remain running. The part goes into the doze state to snoop memory operations on the bus and then back to nap using a <u>QREQ</u>/<u>QACK</u> processor-system handshake protocol.
 - Sleep—Power consumption is further reduced by disabling bus snooping, leaving only the PLL in a locked and running state. All internal functional units are disabled.
 - Deep sleep—When the part is in the sleep state, the system can disable the PLL. The system
 can then disable the SYSCLK source for greater system power savings. Power-on reset
 procedures for restarting and relocking the PLL must be followed upon exiting the deep
 sleep state.
 - Instruction cache throttling provides control of instruction fetching to limit device temperature.
 - A new temperature diode that can determine the temperature of the microprocessor
- Performance monitor can be used to help debug system designs and improve software efficiency.
- In-system testability and debugging features through JTAG boundary-scan capability
- Testability
 - LSSD scan design
 - IEEE Std. 1149.1TM JTAG interface





- Reliability and serviceability
 - Parity checking on system bus
 - Parity checking on the L1 caches and L2 data tags
 - ECC or parity checking on L2 data

3 Comparison with the MPC7447A, MPC7447, MPC7445, and MPC7441

Table 1 compares the key features of the MPC7448 with the key features of the earlier MPC7447A, MPC7447, MPC7445, and MPC7441. All are based on the MPC7450 RISC microprocessor and are architecturally very similar. The MPC7448 is identical to the MPC7447A, but the MPC7448 supports 1 Mbyte of L2 cache with ECC and the use of dynamic frequency switching (DFS) with more bus-to-core ratios.

Microarchitectural Specs	MPC7448	MPC7447A	MPC7447	MPC7445	MPC7441		
Basic Pipeline	Functions						
Logic inversions per cycle	18						
Pipeline stages up to execute			5				
Total pipeline stages (minimum)			7				
Pipeline maximum instruction throughput		:	3 + branch				
Pipeline Re	esources						
Instruction buffer size			12				
Completion buffer size			16				
Renames (integer, float, vector)			16, 16, 16				
Maximum Executi	ion Through	nput					
SFX	3						
Vector	2 (any 2 of 4 units)						
Scalar floating-point	1						
Out-of-Order Window Siz	e in Execut	ion Queues					
SFX integer units		1 en	try $ imes$ 3 queu	ies			
Vector units		In o	rder, 4 queu	es			
Scalar floating-point unit			In order				
Branch Processi	ng Resourc	es					
Prediction structures		BTIC,	BHT, link s	tack			
BTIC size, associativity		128	B-entry, 4-wa	ay			
BHT size			2K-entry				
Link stack depth			8				
Unresolved branches supported			3				
Branch taken penalty (BTIC hit)			1				
Minimum misprediction penalty			6				

Table 1. Microarchitecture Comparison



4 General Parameters

The following list summarizes the general parameters of the MPC7448:

Technology	90 nm CMOS S	0 nm CMOS SOI, nine-layer metal					
Die size	$8.0 \text{ mm} \times 7.3 \text{ m}$	m					
Transistor count	90 million						
Logic design	Mixed static and	Aixed static and dynamic					
Packages	Surface mount 3	Surface mount 360 ceramic ball grid array (HCTE)					
	Surface mount 3	Surface mount 360 ceramic land grid array (HCTE)					
	Surface mount 3	360 ceramic ball grid array with lead-free spheres (HCTE)					
Core power supply	1.30 V	(1700 MHz device)					
	1.25 V	(1600 MHz device)					
	1.20 V	(1420 MHz device)					
	1.15 V	(1000 MHz device)					
I/O power supply	1.5 V, 1.8 V, or	2.5 V					

5 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC7448.

5.1 DC Electrical Characteristics

The tables in this section describe the MPC7448 DC electrical characteristics. Table 2 provides the absolute maximum ratings. See Section 9.2, "Power Supply Design and Sequencing," for power sequencing requirements.

Charao	Symbol	Maximum Value	Unit	Notes		
Core supply voltage			-0.3 to 1.4	V	2	
PLL supply voltage		AV _{DD}	-0.3 to 1.4	V 2		
Processor bus supply voltage	I/O Voltage Mode = 1.5 V	OV _{DD} -0.3 to 1.8		V	3	
	I/O Voltage Mode = 1.8 V		-0.3 to 2.2		3	
	I/O Voltage Mode = 2.5 V		-0.3 to 3.0		3	
Input voltage	Processor bus	V _{in}	-0.3 to OV _{DD} + 0.3	V	4	
	JTAG signals	V _{in}	–0.3 to OV _{DD} + 0.3	V		
Storage temperature range		T _{stg} - 55 to 150 •C				

Table 2. Absolute Maximum Ratings ¹

Notes:

1. Functional and tested operating conditions are given in Table 4. Absolute maximum ratings are stress ratings only and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.

- 2. See Section 9.2, "Power Supply Design and Sequencing" for power sequencing requirements.
- 3. Bus must be configured in the corresponding I/O voltage mode; see Table 3.
- 4. Caution: V_{in} must not exceed OV_{DD} by more than 0.3 V at any time including during power-on reset except as allowed by the overshoot specifications. V_{in} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.



Pin Assignments

6 Pin Assignments

Figure 12 (in Part A) shows the pinout of the MPC7448, 360 high coefficient of thermal expansion ceramic ball grid array (HCTE) package as viewed from the top surface. Part B shows the side profile of the HCTE package to indicate the direction of the top surface view.



Part B







Pinout Listings

Signal Name	Pin Number	Active	I/O	Notes
A[0:35]	E11, H1, C11, G3, F10, L2, D11, D1, C10, G2, D12, L3, G4, T2, F4, V1, J4, R2, K5, W2, J2, K4, N4, J3, M5, P5, N3, T1, V2, U1, N5, W1, B12, C4, G10, B11	High	I/O	2
AACK	R1	Low	Input	
AP[0:4]	C1, E3, H6, F5, G7	High	I/O	2
ARTRY	N2	Low	I/O	3
AV _{DD}	A8	_	Input	
BG	M1	Low	Input	
BMODE0	G9	Low	Input	4
BMODE1	F8	Low	Input	5
BR	D2	Low	Output	
BVSEL0	B7	High	Input	1,6
BVSEL1	E10	High	Input	1, 20
CI	J1	Low	Output	
CKSTP_IN	A3	Low	Input	
CKSTP_OUT	B1	Low	Output	
CLK_OUT	H2	High	Output	
D[0:63]	R15, W15, T14, V16, W16, T15, U15, P14, V13, W13, T13, P13, U14, W14, R12, T12, W12, V12, N11, N10, R11, U11, W11, T11, R10, N9, P10, U10, R9, W10, U9, V9, W5, U6, T5, U5, W7, R6, P7, V6, P17, R19, V18, R18, V19, T19, U19, W19, U18, W17, W18, T16, T18, T17, W3, V17, U4, U8, U7, R7, P6, R8, W8, T8	High	I/O	
DBG	M2	Low	Input	
DFS2	A12	Low	Input	20, 21
DFS4	B6	Low	Input	12, 20, 21
DP[0:7]	T3, W4, T4, W9, M6, V3, N8, W6	High	I/O	
DRDY	R3	Low	Output	7
DTI[0:3]	G1, K1, P1, N1	High	Input	8
EXT_QUAL	A11	High	Input	9
GBL	E2	Low	I/O	
GND	B5, C3, D6, D13, E17, F3, G17, H4, H7, H9, H11, H13, J6, J8, J10, J12, K7, K3, K9, K11, K13, L6, L8, L10, L12, M4, M7, M9, M11, M13, N7, P3, P9, P12, R5, R14, R17, T7, T10, U3, U13, U17, V5, V8, V11, V15		_	
GND	A17, A19, B13, B16, B18, E12, E19, F13, F16, F18, G19, H18, J14, L14, M15, M17, M19, N14, N16, P15, P19	_	—	15
GND_SENSE	G12, N13	—	—	19
ПТ	B2	Low	Output	7
HRESET	D8	Low	Input	
INT	D4	Low	Input	
L1_TSTCLK	G8	High	Input	9
L2_TSTCLK	B3	High	Input	10

Table 11. Pinout	Listing for the	e MPC7448, 36	0 HCTE Package



Signal Name	Pin Number	Active	I/O	Notes
LVRAM	B10	_	_	12, 20, 22
NC (no connect)	A6, A14, A15, B14, B15, C14, C15, C16, C17, C18, C19, D14, D15, D16, D17, D18, D19, E14, E15, F14, F15, G14, G15, H15, H16, J15, J16, J17, J18, J19, K15, K16, K17, K18, K19, L15, L16, L17, L18, L19	_	_	11
LSSD_MODE	E8	Low	Input	6, 12
MCP	C9	Low	Input	
OV _{DD}	B4, C2, C12, D5, F2, H3, J5, K2, L5, M3, N6, P2, P8, P11, R4, R13, R16, T6, T9, U2, U12, U16, V4, V7, V10, V14	—	—	
OVDD_SENSE	E18, G18		—	16
PLL_CFG[0:4]	B8, C8, C7, D7, A7	High	Input	
PLL_CFG[5]	D10	High	Input	9, 20
PMON_IN	D9	Low	Input	13
PMON_OUT	A9	Low	Output	
QACK	G5	Low	Input	
QREQ	P4	Low	Output	
SHD[0:1]	E4, H5	Low	I/O	3
SMI	F9	Low	Input	
SRESET	A2	Low	Input	
SYSCLK	A10		Input	
TA	К6	Low	Input	
TBEN	E1	High	Input	
TBST	F11	Low	Output	
ТСК	C6	High	Input	
TDI	B9	High	Input	6
TDO	A4	High	Output	
TEA	L1	Low	Input	
TEMP_ANODE	N18	—	—	17
TEMP_CATHODE	N19		—	17
TMS	F1	High	Input	6
TRST	A5	Low	Input	6, 14
TS	L4	Low	I/O	3
TSIZ[0:2]	G6, F7, E7	High	Output	
TT[0:4]	E5, E6, F6, E9, C5	High	I/O	
WT	D3	Low	Output	
V _{DD}	H8, H10, H12, J7, J9, J11, J13, K8, K10, K12, K14, L7, L9, L11, L13, M8, M10, M12	—	—	
V _{DD}	A13, A16, A18, B17, B19, C13, E13, E16, F12, F17, F19, G11, G16, H14, H17, H19, M14, M16, M18, N15, N17, P16, P18	_	_	15

Table 11. Pinout Listing for the MPC744	8, 360 HCTE Package (continued)
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Table 11. Pinout Listing for the MPC7448, 360 HCTE Package (continued)

Signal Name	Pin Number	Active	I/O	Notes
VDD_SENSE	G13, N12			18

Notes:

1. OV_{DD} supplies power to the processor bus, JTAG, and all control signals, and is configurable. (V_{DD} supplies power to the processor core, and AV_{DD} supplies power to the PLL after filtering from V_{DD}). To program the I/O voltage, see Table 3. If used, the pull-down resistor should be less than 250 Ω . Because these settings may change in future products, it is recommended BVSEL[0:1] be configured using resistor options, jumpers, or some other flexible means, with the capability to reconfigure the termination of this signal in the future if necessary. For actual recommended value of V_{in} or supply voltages see Table 4.

2. Unused address pins must be pulled down to GND and corresponding address parity pins pulled up to OV_{DD}.

3. These pins require weak pull-up resistors (for example, 4.7 KΩ) to maintain the control signals in the negated state after they have been actively negated and released by the MPC7448 and other bus masters.

4. This signal selects between MPX bus mode (asserted) and 60x bus mode (negated) and will be sampled at HRESET going high.

5. This signal must be negated during reset, by pull-up resistor to OV_{DD} or negation by ¬HRESET (inverse of HRESET), to ensure proper operation.

6. Internal pull up on die.

7. Not used in 60x bus mode.

8. These signals must be pulled down to GND if unused, or if the MPC7448 is in 60x bus mode.

9. These input signals are for factory use only and must be pulled down to GND for normal machine operation.

10. This test signal is recommended to be tied to HRESET; however, other configurations will not adversely affect performance.

11. These signals are for factory use only and must be left unconnected for normal machine operation. Some pins that were NCs on the MPC7447, MPC7445, and MPC7441 have now been defined for other purposes.

- 12. These input signals are for factory use only and must be pulled up to OV_{DD} for normal machine operation.
- 13. This pin can externally cause a performance monitor event. Counting of the event is enabled through software.
- 14. This signal must be asserted during reset, by pull down to GND or assertion by HRESET, to ensure proper operation.
- 15. These pins were NCs on the MPC7447, MPC7445, and MPC7441. See Section 9.3, "Connection Recommendations," for more information.
- 16. These pins were OV_{DD} pins on the MPC7447, MPC7445, and MPC7441. These pins are internally connected to OV_{DD} and are intended to allow an external device (such as a power supply) to detect the I/O voltage level present inside the device package. If unused, it is recommended they be connected to test points to facilitate system debug; otherwise, they may be connected directly to OV_{DD} or left unconnected.
- 17. These pins provide connectivity to the on-chip temperature diode that can be used to determine the die junction temperature of the processor. These pins may be left unterminated if unused.
- 18. These pins are internally connected to V_{DD} and are intended to allow an external device (such as a power supply) to detect the processor core voltage level present inside the device package. If unused, it is recommended they be connected to test points to facilitate system debug; otherwise, they may be connected directly to V_{DD} or left unconnected.
- 19. These pins are internally connected to GND and are intended to allow an external device to detect the processor ground voltage level present inside the device package. If unused, it is recommended they be connected to test points to facilitate system debug; otherwise, they may be connected directly to GND or left unconnected.
- 20. These pins were in the TEST[0:4] factory test pin group on the MPC7447A, MPC7447, MPC7445, and MPC7441. They have been assigned new functions on the MPC7448.
- 21. These pins can be used to enable the supported dynamic frequency switching (DFS) modes via hardware. If both are pulled down, DFS mode is disabled completely and cannot be enabled via software. If unused, they should be pulled up to OV_{DD} to allow software control of DFS. See the *MPC7450 RISC Microprocessor Family Reference Manual* for more information.
- 22. This pin is provided to allow operation of the L2 cache at low core voltages and is for factory use only. See the MPC7450 RISC Microprocessor Family Reference Manual for more information.



8 Package Description

The following sections provide the package parameters and mechanical dimensions for the HCTE package.

8.1 Package Parameters for the MPC7448, 360 HCTE BGA

The package parameters are as provided in the following list. The package type is 25×25 mm, 360-lead high coefficient of thermal expansion ceramic ball grid array (HCTE).

Package outline	$25 \times 25 \text{ mm}$					
Interconnects	360 (19 \times 19 ball array – 1)					
Pitch	1.27 mm (50 mil)					
Minimum module height	2.32 mm					
Maximum module height	2.80 mm					
Ball diameter	0.89 mm (35 mil)					
Coefficient of thermal expansion12.3 ppm/°C						



Package Description

8.2 Mechanical Dimensions for the MPC7448, 360 HCTE BGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7448, 360 HCTE BGA package.



Figure 13. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7448, 360 HCTE BGA Package



8.5 Package Parameters for the MPC7448, 360 HCTE RoHS-Compliant BGA

The package parameters are as provided in the following list. The package type is 25×25 mm, 360-lead high coefficient of thermal expansion ceramic ball grid array (HCTE) with RoHS-compliant lead-free spheres.

Package outline	$25 \times 25 \text{ mm}$					
Interconnects	360 (19 × 19 ball array – 1)					
Pitch	1.27 mm (50 mil)					
Minimum module height	1.92 mm					
Maximum module height	2.40 mm					
Ball diameter	0.75 mm (30 mil)					
Coefficient of thermal expansion12.3 ppm/°C						



System Design Information

	Example Core and VCO Frequency in MHz										
PLL_CFG[0:5]	Bus-to-Core Multiplier ⁵	Corro to VCO	Bus (SYSCLK) Frequency								
		Multiplier ⁵	33.3 MHz	50 MHz	66.6 MHz	75 MHz	83 MHz	100 MHz	133 MHz	167 MHz	200 MHz
100110	11x	1x			733	825	913	1100	1467		
000000	11.5x	1x			766	863	955	1150	1533		
101110	12x	1x		600	800	900	996	1200	1600		
111110	12.5x	1x		625	833	938	1038	1250	1667		
010110	13x	1x		650	865	975	1079	1300			
111000	13.5x	1x		675	900	1013	1121	1350			
110010	14x	1x		700	933	1050	1162	1400			
000110	15x	1x		750	1000	1125	1245	1500			
110110	16x	1x		800	1066	1200	1328	1600			
000010	17x	1x		850	1132	1275	1417	1700			
001010	18x	1x	600	900	1200	1350	1500				
001110	20x	1x	667	1000	1332	1500	1666				
010010	21x	1x	700	1050	1399	1575					
011010	24x	1x	800	1200	1600						
111010	28x	1x	933	1400							
001100	PLL b	oypass		PLL off, S	SYSCLK	clocks co	re circuit	ry directly	/		
111100	PLI	_ off		PL	L off, no	core cloc	king occu	urs			

Table 12. MPC7448 Microprocessor PLL Configuration Example (continued)

Notes:

1. PLL_CFG[0:5] settings not listed are reserved.

2. The sample bus-to-core frequencies shown are for reference only. Some PLL configurations may select bus, core, or VCO frequencies which are not useful, not supported, or not tested for by the MPC7448; see Section 5.2.1, "Clock AC Specifications," for valid SYSCLK, core, and VCO frequencies.

3. In PLL-bypass mode, the SYSCLK input signal clocks the internal processor directly and the PLL is disabled. However, the bus interface unit requires a 2x clock to function. Therefore, an additional signal, EXT_QUAL, must be driven at half the frequency of SYSCLK and offset in phase to meet the required input setup t_{IVKH} and hold time t_{IXKH} (see Table 9). The result will be that the processor bus frequency will be one-half SYSCLK, while the internal processor is clocked at SYSCLK frequency. This mode is intended for factory use and emulator tool use only.

Note: The AC timing specifications given in this document do not apply in PLL-bypass mode.

- 4. In PLL-off mode, no clocking occurs inside the MPC7448 regardless of the SYSCLK input.
- 5. Applicable when DFS modes are disabled. These multipliers change when operating in a DFS mode. See Section 9.7.5, "Dynamic Frequency Switching (DFS)" for more information.
- 6. Bus-to-core multipliers less than 5x require that assertion of AACK be delayed by one or two bus cycles to allow the processor to generate a response to a snooped transaction. See the *MPC7450 RISC Microprocessor Reference Manual* for more information.



System Design Information

9.4 Output Buffer DC Impedance

The MPC7448 processor bus drivers are characterized over process, voltage, and temperature. To measure Z_0 , an external resistor is connected from the chip pad to OV_{DD} or GND. The value of each resistor is varied until the pad voltage is $OV_{DD}/2$. Figure 20 shows the driver impedance measurement.



Figure 20. Driver Impedance Measurement

The output impedance is the average of two components—the resistances of the pull-up and pull-down devices. When data is held low, SW2 is closed (SW1 is open), and R_N is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_N then becomes the resistance of the pull-down devices. When data is held high, SW1 is closed (SW2 is open), and R_P is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_P then becomes the resistance of the pull-down devices to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

Table 15 summarizes the signal impedance results. The impedance increases with junction temperature and is relatively unaffected by bus voltage.

At recommended operating conditions. See Table 4					
	Impedance	Processor Bus	Unit		
Z ₀	Typical	33–42	Ω		
	Maximum	31–51	Ω		

Table 15. Impedance Characteristics

9.5 Pull-Up/Pull-Down Resistor Requirements

The MPC7448 requires high-resistive (weak: 4.7-K Ω) pull-up resistors on several control pins of the bus interface to maintain the control signals in the negated state after they have been actively negated and released by the MPC7448 or other bus masters. These pins are: TS, ARTRY, SHDO, and SHD1.

Some pins designated as being factory test pins must be pulled up to OV_{DD} or down to GND to ensure proper device operation. The pins that must be pulled up to OV_{DD} are LSSD_MODE and TEST[0:3]; the pins that must be pulled down to GND are L1_TSTCLK and TEST[4]. The CKSTP_IN signal should







Figure 23. LGA Package Exploded Cross-Sectional View with Several Heat Sink Options

There are several commercially-available heat sinks for the MPC7448 provided by the following vendors:

Aavid Thermalloy 80 Commercial St. Concord, NH 03301 Internet: www.aavidthermalloy.com	603-224-9988
Alpha Novatech 473 Sapena Ct. #12 Santa Clara, CA 95054 Internet: www.alphanovatech.com	408-567-8082
Calgreg Thermal Solutions 60 Alhambra Road, Suite 1 Warwick, RI 02886 Internet: www.calgregthermalsolutions.com	888-732-6100
International Electronic Research Corporation (IERC) 413 North Moss St. Burbank, CA 91502 Internet: www.ctscorp.com	818-842-7277
Tyco Electronics Chip Coolers [™] P.O. Box 3668 Harrisburg, PA 17105-3668 Internet: www.tycoelectronics.com	800-522-6752
Wakefield Engineering 33 Bridge St. Pelham, NH 03076 Internet: www.wakefield.com	603-635-2800

Ultimately, the final selection of an appropriate heat sink depends on many factors, such as thermal performance at a given air velocity, spatial volume, mass, attachment method, assembly, and cost.



Due to the complexity and variety of system-level boundary conditions for today's microelectronic equipment, the combined effects of the heat transfer mechanisms (radiation, convection, and conduction) may vary widely. For these reasons, we recommend using conjugate heat transfer models for the board as well as system-level designs.

For system thermal modeling, the MPC7448 thermal model is shown in Figure 26. Four volumes represent this device. Two of the volumes, solder ball-air and substrate, are modeled using the package outline size of the package. The other two, die and bump-underfill, have the same size as the die. The silicon die should be modeled $8.0 \times 7.3 \times 0.86$ mm³ with the heat source applied as a uniform source at the bottom of the volume. The bump and underfill layer is modeled as $8.0 \times 7.3 \times 0.07$ mm³ collapsed in the z-direction with a thermal conductivity of 5.0 W/(m • K) in the z-direction. The substrate volume is $25 \times 25 \times 1.14$ mm³ and has 9.9 W/(m • K) isotropic conductivity in the xy-plane and 2.95 W/(m • K) in the direction of the z-axis. The solder ball and air layer are modeled with the same horizontal dimensions as the substrate and is 0.8 mm thick. For the LGA package the solder and air layer is 0.1 mm thick, but the material properties are the same. It can also be modeled as a collapsed volume using orthotropic material properties: 0.034 W/(m • K) in the xy-plane direction and 11.2 W/(m • K) in the direction of the z-axis.

$\begin{tabular}{ c c c c } \hline \hline Die & \hline \hline Die & \hline \hline Die & \hline \hline \hline \hline & \hline $	Conductivity	Value	Unit				
zBump and UnderfillSiliconTemperature- dependentW/(m • K)Bump and Underfill (8.0 × 7.3 × 0.07 mm³)Solder and Air k_z 5.0W/(m • K) k_z 5.0W/(m • K)Substrate (25 × 25 × 1.14 mm³)W/(m • K) k_χ 9.9W/(m • K) k_z 2.95Die k_x 0.034W/(m • K) k_χ 0.034W/(m • K)	Die (8		,	•	Die		
SiliconTemperature- dependent $W/(m \cdot K)$ Bump and Underfill (8.0 × 7.3 × 0.07 mm³) $Solder and Air$ kz5.0 $W/(m \cdot K)$ kx9.9 $W/(m \cdot K)$ kz9.9 $W/(m \cdot K)$ kz2.95Solder Ball and Air (25 × 25 × 0.8 mm³) Die kx0.034 $W/(m \cdot K)$	- (-	,		z		Bump and Underfill	
Solder and AirSolder and AirKz 5.0 W/(m • K)Substrate (25 × 25 × 1.14 mm³)Side View of Model (Not to Scale) k_x 9.9 W/(m • K) k_y 9.9 W/(m • K) k_z 2.95 Solder Ball and Air (25 × 25 × 0.8 mm³)Die k_x 0.034 W/(m • K)	Silicon	Temperature- dependent	W/(m • K)		Substrate		
Substrate (3.5 × 1.6 × 0.01 mm) k_z 5.0 $W/(m \cdot K)$ Substrate (25 × 25 × 1.14 mm³) $W/(m \cdot K)$ k_x 9.9 $W/(m \cdot K)$ k_z 2.95Solder Ball and Air (25 × 25 × 0.8 mm³) Die k_x 0.034 $W/(m \cdot K)$	$\frac{1}{10000000000000000000000000000000000$					Solder and Air	
$ \begin{array}{ c c c c } \hline k_z & 5.0 & W/(m \cdot K) \\ \hline Substrate (25 \times 25 \times 1.14 mm^3) \\ \hline k_x & 9.9 & W/(m \cdot K) \\ \hline k_y & 9.9 & \\ \hline k_z & 2.95 & \\ \hline \hline Solder Ball and Air (25 \times 25 \times 0.8 mm^3) \\ \hline k_x & 0.034 & W/(m \cdot K) \\ \hline k_y & 0.034 & \\ \hline \end{array} $				-	Side	View of Model (Not to Scale)	
Substrate (25 × 25 × 1.14 mm ³) k_x 9.9 W/(m • K) k_y 9.9 W/(m • K) k_z 2.95 Die Die k_x 0.034 W/(m • K) k_y 0.034 W/(m • K)	kz	5.0	W/(m ∙ K)				
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Substrate (25 \times 25 \times 1.14 mm ³)				<u> </u>	→	
k _y 9.9 Substrate k _z 2.95 k_z b_z Solder Ball and Air (25 × 25 × 0.8 mm ³) Die Die k _x 0.034 $W/(m \cdot K)$ $M/(m \cdot K)$	k _x	9.9	W/(m • K)			Orthostwate	
$\begin{tabular}{ c c c c c } \hline k_z & 2.95 & \\ \hline Solder Ball $and Air (25 \times 25 \times 0.8 mm^3)$ \\ \hline k_x & 0.034 & \\ \hline k_y & 0.034 & \\ \hline \end{tabular}$	k _y	9.9				Substrate	
Solder Ball and Air (25 × 25 × 0.8 mm ³) k _x 0.034 W/(m • K) k _y 0.034 W/(m • K)	k _z	2.95					
k _x 0.034 W/(m ⋅ K) k _y 0.034 Image: W/(m ⋅ K)	Solder Ball a			Die			
k _y 0.034	k _x	0.034	W/(m • K)	1			
	k _y	0.034					
k _z 11.2 y	k _z	11.2		У			

Top View of Model (Not to Scale)

Figure 26. Recommended Thermal Model of MPC7448



Solving for T, the equation becomes:

$$\mathbf{nT} = \frac{\mathbf{V}_{\mathrm{H}} - \mathbf{V}_{\mathrm{L}}}{1.986 \times 10^{-4}}$$

9.7.5 Dynamic Frequency Switching (DFS)

The DFS feature in the MPC7448 adds the ability to divide the processor-to-system bus ratio by two or four during normal functional operation. Divide-by-two mode is enabled by setting the HID1[DFS2] bit in software or by asserting the $\overline{DFS2}$ pin via hardware. The MPC7448 can be returned for full speed by clearing HID1[DFS2] or negating $\overline{DFS2}$. Similarly, divide-by-four mode is enabled by setting HID1[DFS4] in software or by asserting the $\overline{DFS4}$ pin. In all cases, the frequency change occurs in 1 clock cycle and no idle waiting period is required to switch between modes. Note that asserting either $\overline{DFS2}$ or $\overline{DFS4}$ overrides software control of DFS, and that asserting both $\overline{DFS2}$ and $\overline{DFS4}$ disables DFS completely, including software control. Additional information regarding DFS can be found in the *MPC7450 RISC Microprocessor Family Reference Manual*. Note that minimum core frequency requirements must be observed when enabling DFS, and the resulting core frequency must meet the requirements for f_{core DFS} given in Table 8.

9.7.5.1 Power Consumption with DFS Enabled

Power consumption with DFS enabled can be approximated using the following formula:

$$\mathbf{P}_{\mathbf{DFS}} = \begin{bmatrix} \overline{\mathbf{f}_{\mathbf{DFS}}} & (\mathbf{P} - \mathbf{P}_{\mathbf{DS}}) \end{bmatrix} + \mathbf{P}_{\mathbf{DS}}$$

Where:

 P_{DFS} = Power consumption with DFS enabled

 f_{DFS} = Core frequency with DFS enabled

f = Core frequency prior to enabling DFS

P = Power consumption prior to enabling DFS (see Table 7)

 P_{DS} = Deep sleep mode power consumption (see Table 7)

The above is an approximation only. Power consumption with DFS enabled is not tested or guaranteed.

9.7.5.2 Bus-to-Core Multiplier Constraints with DFS

DFS is not available for all bus-to-core multipliers as configured by PLL_CFG[0:5] during hard reset. The complete listing is shown in Table 16. Shaded cells represent DFS modes that are not available for a particular PLL_CFG[0:5] setting. Should software or hardware attempt to transition to a multiplier that is not supported, the device will remain at its current multiplier. For example, if a transition from DFS-disabled to an unsupported divide-by-2 or divide-by-4 setting is attempted, the bus-to-core multiplier will remain at the setting configured by the PLL_CFG[0:5] pins. In the case of an attempted transition from a supported divide-by-2 mode to an unsupported divide-by-4 mode, the device will remain in divide-by-2 mode. In all cases, the HID1[PC0-5] bits will correctly reflect the current bus-to-core frequency multiplier.

System Design Information

DFS mode dis	abled	DFS divide-by-2 ((HID1[DFS2] = 1	mode enabled or DFS2 = 0)	DFS divide-by-4 m (HID1[DFS4] = 1 o	ode enabled r DFS4 = 0)
Bus-to-Core Multiplier Configured by PLL_CFG[0:5] (see Table 12)	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³
2x ⁴	010000	N/A (unchanged) ¹	unchanged ¹	N/A (unchanged) ¹	unchanged ¹
3x ⁴	100000	N/A (unchanged) ¹	unchanged ¹	N/A (unchanged) ¹	unchanged ¹
4x ⁴	101000	2x ⁴	010000	N/A (unchanged) ¹	unchanged ¹
5x	101100	2.5x ⁴	010101	N/A (unchanged) ¹	unchanged ¹
5.5x	100100	2.75x ⁴	110101 ²	N/A (unchanged) ¹	unchanged ¹
6x	110100	3x ⁴	100000	N/A (unchanged) ¹	unchanged ¹
6.5x	010100	3.25x ⁴	100000 ²	N/A (unchanged) ¹	unchanged ¹
7x	001000	3.5x ⁴	110101	N/A (unchanged) ¹	unchanged ¹
7.5x	000100	3.75x ⁴	110101 ²	N/A (unchanged) ¹	unchanged ¹
8x	110000	4x ⁴	101000 ⁴	2x ⁴	010000
8.5x	011000	4.25x ⁴	101000 ²	N/A (unchanged) ¹	unchanged ¹
9x	011110	4.5x ⁴	011101	2.25x ⁴	010000 ²
9.5x	011100	4.75x ⁴	011101 ²	N/A (unchanged) ¹	unchanged ¹
10x	101010	5x	101100	2.5x ⁴	010101
10.5x	100010	5.25x	101100 ²	N/A (unchanged) ¹	unchanged ¹
11x	100110	5.5x	100100	2.75x ⁴	010101 ²
11.5x	000000	5.75x	100100 ²	N/A (unchanged) ¹	unchanged ¹
12x	101110	6x	110100	3x ⁴	100000
12.5x	111110	6.25x	110100 ²	N/A (unchanged) ¹	unchanged ¹
13x	010110	6.5x	010100	3.25x ⁴	100000 ²
13.5x	111000	6.75	010100 ²	N/A (unchanged) ¹	unchanged ¹
14x	110010	7x	001000	3.5x ⁴	110101
15x	000110	7.5x	000100	3.75x ⁴	110101 ²
16x	110110	8x	110000	4x ⁴	101000
17x	000010	8.5x	011000	4.25x ⁴	101000 ²
18x	001010	9x	011110	4.5x ⁴	011101
20x	001110	10x	101010	5x	101100
21x	010010	10.5x	100010	5.25x	101100 ²

Table 16. Valid Divide Ratio Configurations



		7		
			Δ	

DFS mode dis	abled	DFS divide-by-2 (HID1[DFS2] = 1	mode enabled or DFS2 = 0)	DFS divide-by-4 mo (HID1[DFS4] = 1 o	ode enabled r DFS4 = 0)
Bus-to-Core Multiplier Configured by PLL_CFG[0:5] (see Table 12)	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³	Bus-to-Core Multiplier	HID1[PC0-5] ³
24x	011010	12x	101110	6x	110100
28x	111010	14x	110010	7x	001000

Table 16. Valid Divide Ratio Configurations (continued	Table	16.	Valid	Divide	Ratio	Configura	tions	(continued
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Notes:

1. DFS mode is not supported for this combination of DFS mode and PLL_CFG[0:5] setting. As a result, the processor will ignore these settings and remain at the previous multiplier, as reflected by the HID1[PC0-PC5] bits.

2. Though supported by the MPC7448 clock circuitry, multipliers of *n*.25x and *n*.75x cannot be expressed as valid PLL configuration codes. As a result, the values displayed in HID1[PC0-PC5] are rounded down to the nearest valid PLL configuration code. However, the actual bus-to-core multiplier is as stated in this table.

- 3. Note that in the HID1 register of the MPC7448, the PC0, PC1, PC2, PC3, PC4, and PC5 bits are bits 15, 16, 17, 18, 19, and 14 (respectively). See the *MPC7450 RISC Microprocessor Reference Manual* for more information.
- 4. Special considerations regarding snooped transactions must be observed for bus-to-core multipliers less than 5x. See the *MPC7450 RISC Microprocessor Reference Manual* for more information.

9.7.5.3 Minimum Core Frequency Requirements with DFS

In many systems, enabling DFS can result in very low processor core frequencies. However, care must be taken to ensure that the resulting processor core frequency is within the limits specified in Table 8. Proper operation of the device is not guaranteed at core frequencies below the specified minimum f_{core} .

10 Document Revision History

Table 17 provides a revision history for this hardware specification.

Table 17.	Document	Revision	History
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Revision	Date	Substantive Change(s)
4	3/2007	Table 19: Added 800 MHz processor frequency.
3	10/2006	Section 9.7, "Power and Thermal Management Information": Updated contact information. Table 18, Table 20, and Table 19: Added Revision D PVR. Table 19: Added 600 processor frequency, additional product codes, date codes for 1400 processor frequency, and footnotes 1 and 2. Table 20: Added PPC product code and footnote 1. Table 19 and Table 20: Added Revision D information for 1267 processor frequency.



Document Revision History

Revision	Date	Substantive Change(s)
2		Table 6: Added separate input leakage specification for BVSEL0, <u>LSSD_MODE</u> , <u>TCK</u> , TDI, TMS, <u>TRST</u> signals to correctly indicate leakage current for signals with internal pull-up resistors.
		Section 5.1: Added paragraph preceding Table 7 and edited notes in Table 7 to clarify core frequencies at which power consumption is measured.
		Section 5.3: Removed voltage derating specifications; this feature has been made redundant by new device offerings and is no longer supported.
		Changed names of "Typical–Nominal" and "Typical–Thermal" power consumption parameters to "Typical" and "Thermal", respectively. (Name change only–no specifications were changed.)
		Table 11: Revised Notes 16, 18, and 19 to reflect current recommendations for connection of SENSE pins.
		Section 9.3: Added paragraph explaining connection recommendations for SENSE pins. (See also Table 11 entry above.)
		Table 19: Updated table to reflect changes in specifications for MC7448xxnnnnNC devices. Table 9: Changed all instances of TT[0:3] to TT[0:4]
		Removed mention of these input signals from output valid times and output hold times:
		• AACK, CKSTP_IN, DT[0:3]
		Figure 17: Modified diagram slightly to correctly snow constraint on SYSCLK ramping is related to V _{DD}
		Added Table 20 to reflect introduction of extended temperature devices and associated hardware
		specification addendum.
1		Added 1600 MHz, 1420 MHz, and 1000 MHz devices
		Section 4: corrected die size
		Table 2: Revised Note 4 to consider overshoot/undershoot and combined with Note 5.
		Table 4. Revised operating voltage for 1700 MHz device from \pm 50 mV to \pm 20 mV $/$ =50 mV.
		Table 11: Added voltage derating information for 1700 MHz devices: this feature is not supported at this
		time for other speed grades.
		Added transient specifications for VDD power supply in Section 9.2.3, added Table 15 and Figure 19 and renumbered subsequent tables and figures.
		Moved Decoupling Recommendations from Section 9.4 to Section 9.2.4 and renumbered subsequent sections.
		Section 9.2.1: Revised power sequencing requirements.
		Section 9.7.4: Added thermal diode ideality factor information (previously TBD).
		Table 17: Expanded table to show HID1 register values when DFS modes are enabled.
		Section 11.2: updated to include additional N-spec device speed grades
		Tables 18 and 19: corrected PVR values and added "MC" product code prefix
0		Initial public release.

Table 17. Document Revision History (continued)

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